



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

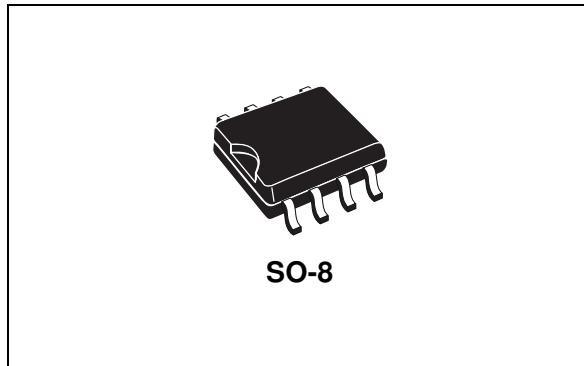
Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

High-side driver

Features

| Type | R _{DS(on)} | I _{OUT} | V _{CC} |
|-----------|---------------------|------------------|-----------------|
| VN750PS-E | 60 mΩ | 6 A | 36 V |

- ECOPACK® : lead free and RoHS compliant
- Automotive Grade: compliance with AEC guidelines
- CMOS compatible input
- On-state open-load detection
- Off-state open-load detection
- Shorted load protection
- Undervoltage and overvoltage shutdown
- Protection against loss of ground
- Very low standby current
- Reverse battery protection



SO-8

Description

The VN750PS-E is a monolithic device designed in STMicroelectronics™ VIPower™ M0-3 Technology intended for driving any kind of load with one side connected to ground.

Active V_{CC} pin voltage clamp protects the device against low energy spikes (see ISO7637 transient compatibility table). Active current limitation combined with thermal shutdown and automatic restart help protect the device against overload.

The device detects open load condition in on and off-state. Output shorted to V_{CC} is detected in the off-state. Device automatically turns off in case of ground pin disconnection.

Table 1. Device summary

| Package | Order codes | |
|---------|-------------|---------------|
| | Tube | Tape and reel |
| SO-8 | VN750PS-E | VN750PSTR-E |

Contents

| | | |
|----------|--|-----------|
| 1 | Block diagram and pin description | 5 |
| 2 | Electrical specifications | 6 |
| 2.1 | Absolute maximum ratings | 6 |
| 2.2 | Thermal data | 7 |
| 2.3 | Electrical characteristics | 8 |
| 2.4 | Electrical characteristics curves | 13 |
| 2.5 | GND protection network against reverse battery | 16 |
| 2.6 | Load dump protection | 17 |
| 2.7 | Microcontroller I/Os protection | 17 |
| 2.8 | Open-load detection in off-state | 17 |
| 2.9 | SO-8 maximum demagnetization energy ($V_{CC} = 13.5$ V) | 19 |
| 3 | Package and PCB thermal data | 20 |
| 3.1 | SO-8 thermal data | 20 |
| 4 | Package and packing information | 23 |
| 4.1 | SO-8 package information | 23 |
| 4.2 | SO-8 packing information | 25 |
| 5 | Revision history | 26 |

List of tables

| | | |
|-----------|--|----|
| Table 1. | Device summary | 1 |
| Table 2. | Suggested connections for unused and not connected pins | 5 |
| Table 3. | Absolute maximum ratings | 6 |
| Table 4. | Thermal data..... | 7 |
| Table 5. | Electrical characteristics | 8 |
| Table 6. | Truth table..... | 10 |
| Table 7. | Electrical transient requirements on V _{CC} pin (part 1/3)..... | 11 |
| Table 8. | Electrical transient requirements on V _{CC} pin (part 2/3)..... | 11 |
| Table 9. | Electrical transient requirements on V _{CC} pin (part 3/3)..... | 11 |
| Table 10. | Thermal parameter | 22 |
| Table 11. | SO-8 mechanical data | 24 |
| Table 12. | Document revision history | 26 |

List of figures

| | | |
|------------|---|----|
| Figure 1. | Block diagram | 5 |
| Figure 2. | Configuration diagram (top view) | 5 |
| Figure 3. | Current and voltage conventions | 6 |
| Figure 4. | Status timings | 10 |
| Figure 5. | Switching time waveforms | 10 |
| Figure 6. | Waveforms | 12 |
| Figure 7. | Off-state output current | 13 |
| Figure 8. | High level input current | 13 |
| Figure 9. | Input clamp voltage | 13 |
| Figure 10. | Status leakage current | 13 |
| Figure 11. | Status low output voltage | 13 |
| Figure 12. | Status clamp voltage | 13 |
| Figure 13. | On-state resistance vs T_{case} | 14 |
| Figure 14. | On-state resistance vs V_{CC} | 14 |
| Figure 15. | Open-load on-state detection threshold | 14 |
| Figure 16. | Input high level | 14 |
| Figure 17. | Input low level | 14 |
| Figure 18. | Input hysteresis voltage | 14 |
| Figure 19. | Overshoot shutdown | 15 |
| Figure 20. | Open-load off-state voltage detection threshold | 15 |
| Figure 21. | Turn-on voltage slope | 15 |
| Figure 22. | Turn-off voltage slope | 15 |
| Figure 23. | I_{lim} vs T_{case} | 15 |
| Figure 24. | Application schematic | 16 |
| Figure 25. | Open-load detection in off-state | 18 |
| Figure 26. | SO-8 maximum turn-off current versus inductance | 19 |
| Figure 27. | PC board | 20 |
| Figure 28. | $R_{thj-amb}$ vs PCB copper area in open box free air condition | 20 |
| Figure 29. | SO-8 thermal impedance junction ambient single pulse | 21 |
| Figure 30. | Thermal fitting model of a single channel | 21 |
| Figure 31. | SO-8 package dimensions | 23 |
| Figure 32. | SO-8 tube shipment (no suffix) | 25 |
| Figure 33. | SO-8 tape and reel shipment (suffix "TR") | 25 |

1 Block diagram and pin description

Figure 1. Block diagram

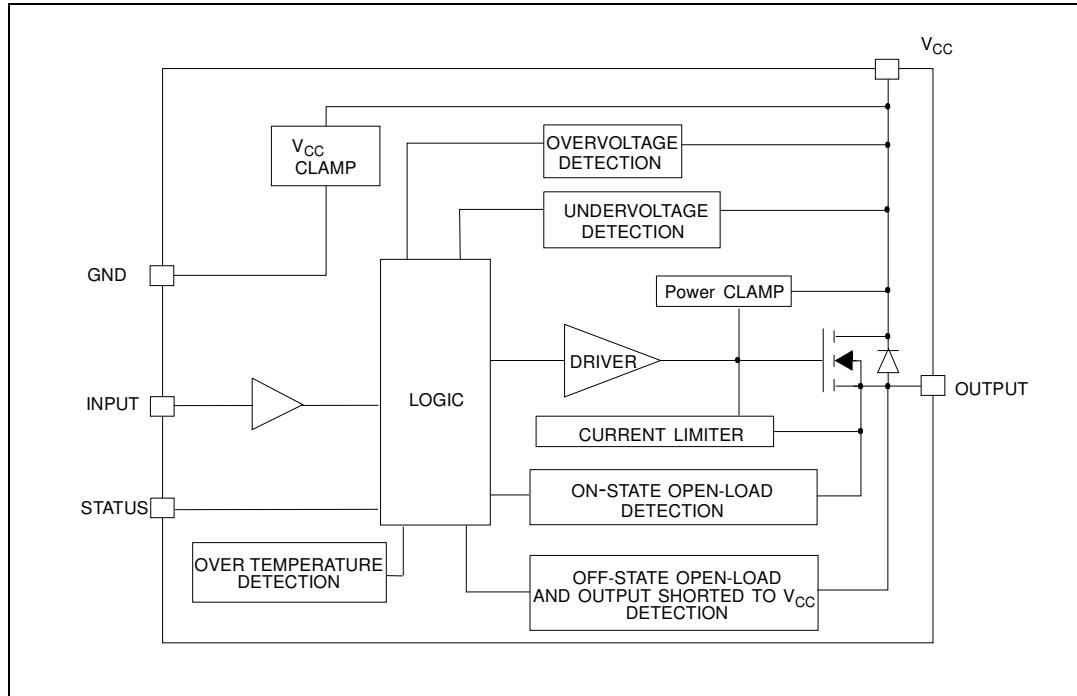


Figure 2. Configuration diagram (top view)

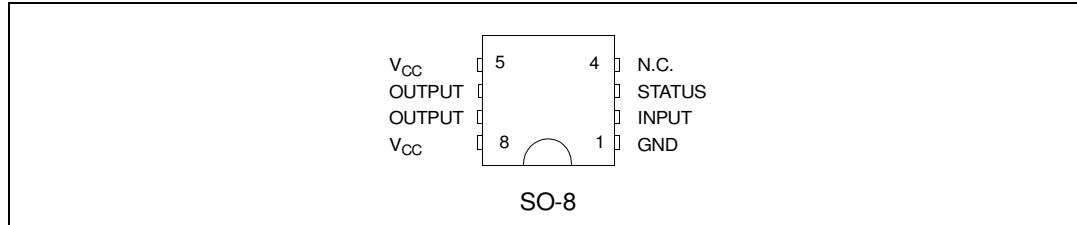
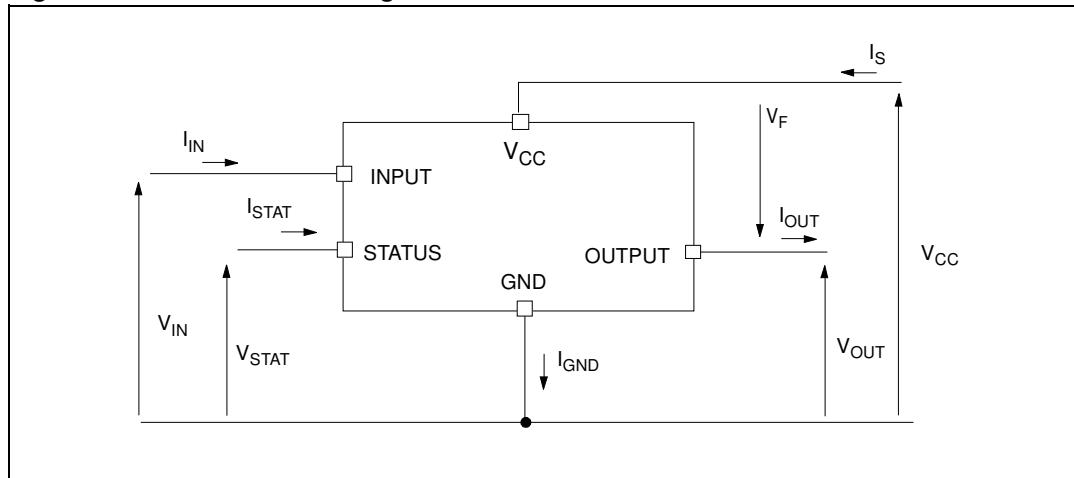


Table 2. Suggested connections for unused and not connected pins

| Connection/pin | Status | N.C. | Output | Input |
|----------------|--------|------|--------|------------------------|
| Floating | X | X | X | X |
| To ground | | X | | Through 10 KΩ resistor |

2 Electrical specifications

Figure 3. Current and voltage conventions



2.1 Absolute maximum ratings

Stress values that exceed those listed in the “Absolute maximum ratings” table can cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions greater than those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics sure program and other relevant quality documents.

Table 3. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|------------|---|------------------------------|------|
| V_{CC} | DC supply voltage | 41 | V |
| $-V_{CC}$ | Reverse DC supply voltage | - 0.3 | V |
| $-I_{gnd}$ | DC reverse ground pin current | - 200 | mA |
| I_{OUT} | DC output current | Internally limited | A |
| $-I_{OUT}$ | Reverse DC output current | - 6 | A |
| I_{IN} | DC input current | $+/- 10$ | mA |
| I_{STAT} | DC status current | $+/- 10$ | mA |
| V_{ESD} | Electrostatic discharge (human body model: $R = 1.5 \text{ k}\Omega$; $C = 100 \text{ pF}$) - Input - Status - Output - V_{CC} | 4000 4000 5000 5000 | V |

Table 3. Absolute maximum ratings (continued)

| Symbol | Parameter | Value | Unit |
|-----------|---|--------------------|------------------|
| E_{MAX} | Maximum switching energy ($L = 1.8 \text{ mH}$; $R_L = 0 \Omega$; $V_{bat} = 13.5 \text{ V}$; $T_{jstart} = 150 \text{ }^\circ\text{C}$; $I_L = 9 \text{ A}$) | 100 | mJ |
| P_{tot} | Power dissipation $T_C = 25 \text{ }^\circ\text{C}$ | 4.2 | W |
| T_j | Junction operating temperature | Internally limited | $^\circ\text{C}$ |
| T_c | Case operating temperature | - 40 to 150 | $^\circ\text{C}$ |
| T_{stg} | Storage temperature | - 55 to 150 | $^\circ\text{C}$ |

2.2 Thermal data

Table 4. Thermal data

| Symbol | Parameter | Max. value | Unit |
|----------------|-------------------------------------|-------------------|--------------------|
| $R_{thj-lead}$ | Thermal resistance junction-lead | 30 | $^\circ\text{C/W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient | 93 ⁽¹⁾ | $^\circ\text{C/W}$ |
| | | 82 ⁽²⁾ | $^\circ\text{C/W}$ |

1. When mounted on a standard single-sided FR-4 board with 0.5 cm^2 of Cu (at least 35 μm thick) connected to all V_{CC} pins. Horizontal mounting and no artificial air flow.
2. When mounted on a standard single-sided FR-4 board with 2 cm^2 of Cu (at least 35 μm thick) connected to all V_{CC} pins. Horizontal mounting and no artificial air flow.

2.3 Electrical characteristics

Values specified in this section are for $8 \text{ V} < V_{CC} < 36 \text{ V}$; $-40^\circ\text{C} < T_j < 150^\circ\text{C}$, unless otherwise stated.

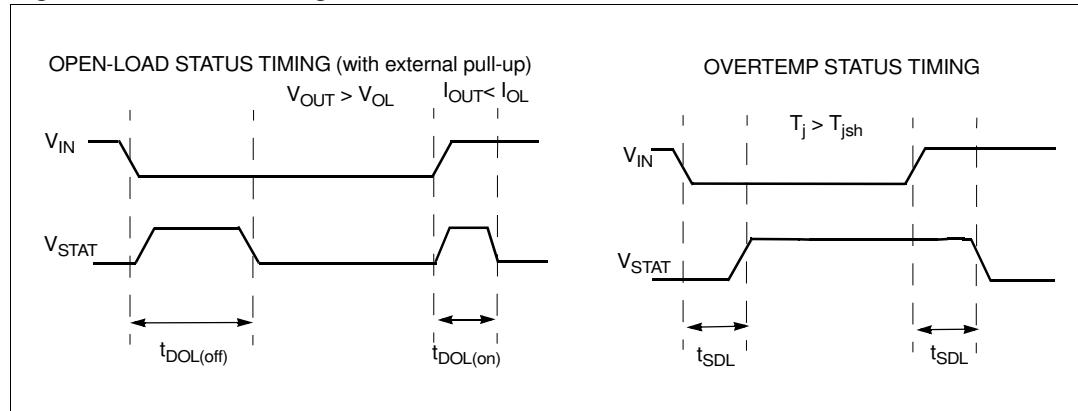
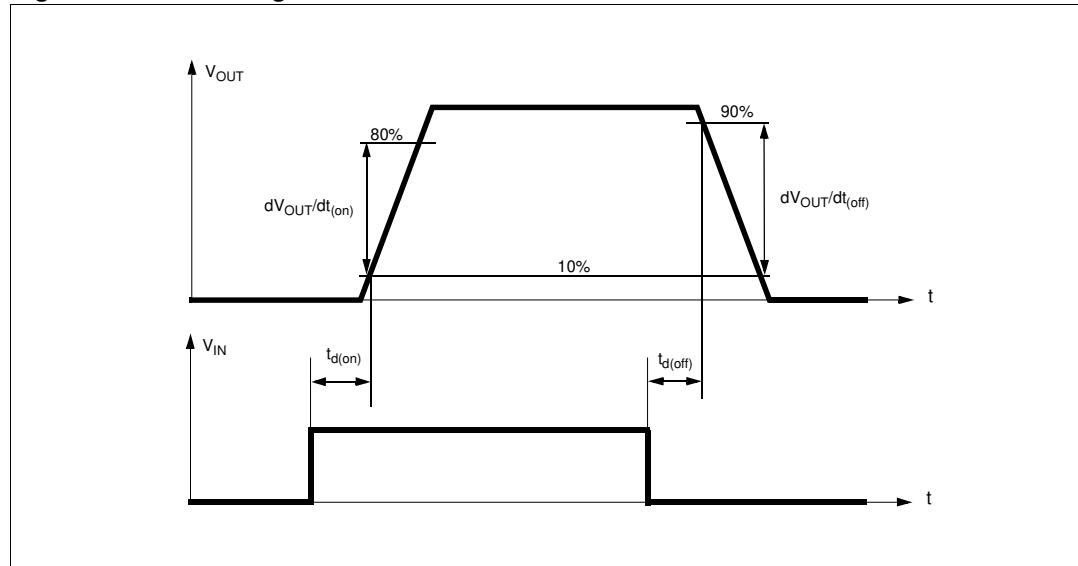
Table 5. Electrical characteristics

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|----------------------------------|---|-------------------------------|------|------|------------------------|
| Power | | | | | | |
| V_{CC} | Operating supply voltage | | 5.5 | 13 | 36 | V |
| V_{USD} | Undervoltage shutdown | | 3 | 4 | 5.5 | V |
| $V_{USDhyst}$ | Undervoltage shutdown hysteresis | | | 0.5 | | V |
| V_{OV} | Oversupply shutdown | | 36 | | | V |
| R_{ON} | On-state resistance | $I_{OUT} = 2 \text{ A}; T_j = 25^\circ\text{C}; V_{CC} > 8 \text{ V}$ | | | 60 | $\text{m}\Omega$ |
| | | $I_{OUT} = 2 \text{ A}; V_{CC} > 8 \text{ V}$ | | | 120 | $\text{m}\Omega$ |
| I_S | Supply current | Off-state; $V_{CC} = 13 \text{ V}$; $V_{IN} = V_{OUT} = 0 \text{ V}$ | | 10 | 25 | μA |
| | | Off-state; $V_{CC} = 13 \text{ V}$; $V_{IN} = V_{OUT} = 0 \text{ V}; T_j = 25^\circ\text{C}$ | | 10 | 20 | μA |
| | | On-state; $V_{CC} = 13 \text{ V}$; $V_{IN} = 5 \text{ V}; I_{OUT} = 0 \text{ A}$ | | 2 | 3.5 | mA |
| $I_{L(off1)}$ | Off-state output current | $V_{IN} = V_{OUT} = 0 \text{ V}$ | 0 | | 50 | μA |
| $I_{L(off2)}$ | Off-state output current | $V_{IN} = 0 \text{ V}; V_{OUT} = 3.5 \text{ V}$ | -75 | | 0 | μA |
| $I_{L(off3)}$ | Off-state output current | $V_{IN} = V_{OUT} = 0 \text{ V}; V_{CC} = 13 \text{ V}; T_j = 125^\circ\text{C}$ | | | 5 | μA |
| $I_{L(off4)}$ | Off-state output current | $V_{IN} = V_{OUT} = 0 \text{ V}; V_{CC} = 13 \text{ V}; T_j = 25^\circ\text{C}$ | | | 3 | μA |
| Switching ($V_{CC} = 13 \text{ V}$) | | | | | | |
| $t_{d(on)}$ | Turn-on delay time | $R_L = 6.5 \Omega$ from V_{IN} rising edge to $V_{OUT} = 1.3 \text{ V}$ | | 40 | | μs |
| $t_{d(off)}$ | Turn-off delay time | $R_L = 6.5 \Omega$ from V_{IN} falling edge to $V_{OUT} = 11.7 \text{ V}$ | | 30 | | μs |
| $dV_{OUT}/dt_{(on)}$ | Turn-on voltage slope | $R_L = 6.5 \Omega$ from $V_{OUT} = 1.3 \text{ V}$ to $V_{OUT} = 10.4 \text{ V}$ | See Figure 21 | | | $\text{V}/\mu\text{s}$ |
| $dV_{OUT}/dt_{(off)}$ | Turn-off voltage slope | $R_L = 6.5 \Omega$ from $V_{OUT} = 11.7 \text{ V}$ to $V_{OUT} = 1.3 \text{ V}$ | See Figure 22 | | | $\text{V}/\mu\text{s}$ |
| Input pin | | | | | | |
| V_{IL} | Input low level | | | | 1.25 | V |
| I_{IL} | Low level input current | $V_{IN} = 1.25 \text{ V}$ | 1 | | | μA |
| V_{IH} | Input high level | | 3.25 | | | V |

Table 5. Electrical characteristics (continued)

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|---|---|-------------|-------------|-------------|------------------|
| I_{IH} | High level input current | $V_{IN} = 3.25 \text{ V}$ | | | 10 | μA |
| V_{hyst} | Input hysteresis voltage | | 0.5 | | | V |
| V_{ICL} | Input clamp voltage | $I_{IN} = 1 \text{ mA}$ | 6 | 6.8 | 8 | V |
| | | $I_{IN} = -1 \text{ mA}$ | | -0.7 | | V |
| V_{CC} output diode | | | | | | |
| V_F | Forward on voltage | $-I_{OUT} = 1.3 \text{ A}; T_j = 150 \text{ }^\circ\text{C}$ | | | 0.6 | V |
| Status pin | | | | | | |
| V_{STAT} | Status low output voltage | $I_{STAT} = 1.6 \text{ mA}$ | | | 0.5 | V |
| I_{LSTAT} | Status leakage current | Normal operation; $V_{STAT} = 5 \text{ V}$ | | | 10 | μA |
| C_{STAT} | Status pin input capacitance | Normal operation; $V_{STAT} = 5 \text{ V}$ | | | 100 | pF |
| V_{SCL} | Status clamp voltage | $I_{STAT} = 1 \text{ mA}$ | 6 | 6.8 | 8 | V |
| | | $I_{STAT} = -1 \text{ mA}$ | | -0.7 | | V |
| Protections⁽¹⁾ | | | | | | |
| T_{TSD} | Shutdown temperature | | 150 | 175 | 200 | $^\circ\text{C}$ |
| T_R | Reset temperature | | 135 | | | $^\circ\text{C}$ |
| T_{hyst} | Thermal hysteresis | | 7 | 15 | | $^\circ\text{C}$ |
| t_{SDL} | Status delay in overload condition | $T_j > T_{jsh}$ | | | 20 | ms |
| I_{lim} | Current limitation | $9 \text{ V} < V_{CC} < 36 \text{ V}$ | 6 | 9 | 15 | A |
| | | $5 \text{ V} < V_{CC} < 36 \text{ V}$ | | | 15 | A |
| V_{demag} | Turn-off output clamp voltage | $I_{OUT} = 2 \text{ A}; V_{IN} = 0 \text{ V}; L = 6 \text{ mH}$ | V_{CC-41} | V_{CC-48} | V_{CC-55} | V |
| Open-load detection | | | | | | |
| I_{OL} | Open-load on-state detection threshold | $V_{IN} = 5 \text{ V}$ | 50 | | 200 | mA |
| $t_{DOL(on)}$ | Open-load on-state detection delay | $I_{OUT} = 0 \text{ A}$ | | | 200 | μs |
| V_{OL} | Open-load off-state voltage detection threshold | $V_{IN} = 0 \text{ V}$ | 1.5 | | 3.5 | V |
| $t_{DOL(off)}$ | Open-load detection delay at turn-off | | | | 1000 | μs |

1. To ensure long term reliability under heavy overload or short circuit conditions, protection and related diagnostic signals must be used together with a proper software strategy. If the device operates under abnormal conditions this software must limit the duration and number of activation cycles.

Figure 4. Status timings**Figure 5. Switching time waveforms****Table 6. Truth table**

| Conditions | Input | Output | Status |
|--------------------|-------|--------|---------------------|
| Normal operation | L | L | H |
| | H | H | H |
| Current limitation | L | L | H |
| | H | X | $(T_j < T_{TSD})$ H |
| | H | X | $(T_j > T_{TSD})$ L |
| Over temperature | L | L | H |
| | H | L | L |
| Undervoltage | L | L | X |
| | H | L | X |
| Overvoltage | L | L | H |
| | H | L | H |

Table 6. Truth table (continued)

| Conditions | Input | Output | Status |
|---------------------------|-------|--------|--------|
| Output voltage > V_{OL} | L | H | L |
| | H | H | H |
| Output current < I_{OL} | L | L | H |
| | H | H | L |

Table 7. Electrical transient requirements on V_{CC} pin (part 1/3)

| ISO T/R 7637/1 test pulse | Test levels | | | | |
|------------------------------|-------------|---------|---------|---------|-------------------------|
| | I | II | III | IV | Delays and impedance |
| 1 | -25 V | -50 V | -75 V | -100 V | 2 ms 10 Ω |
| 2 | +25 V | +50 V | +75 V | +100 V | 0.2 ms 10 Ω |
| 3a | -25 V | -50 V | -100 V | -150 V | 0.1 μs 50 Ω |
| 3b | +25 V | +50 V | +75 V | +100 V | 0.1 μs 50 Ω |
| 4 | -4 V | -5 V | -6 V | -7 V | 100 ms, 0.01 Ω |
| 5 | +26.5 V | +46.5 V | +66.5 V | +86.5 V | 400 ms, 2 Ω |

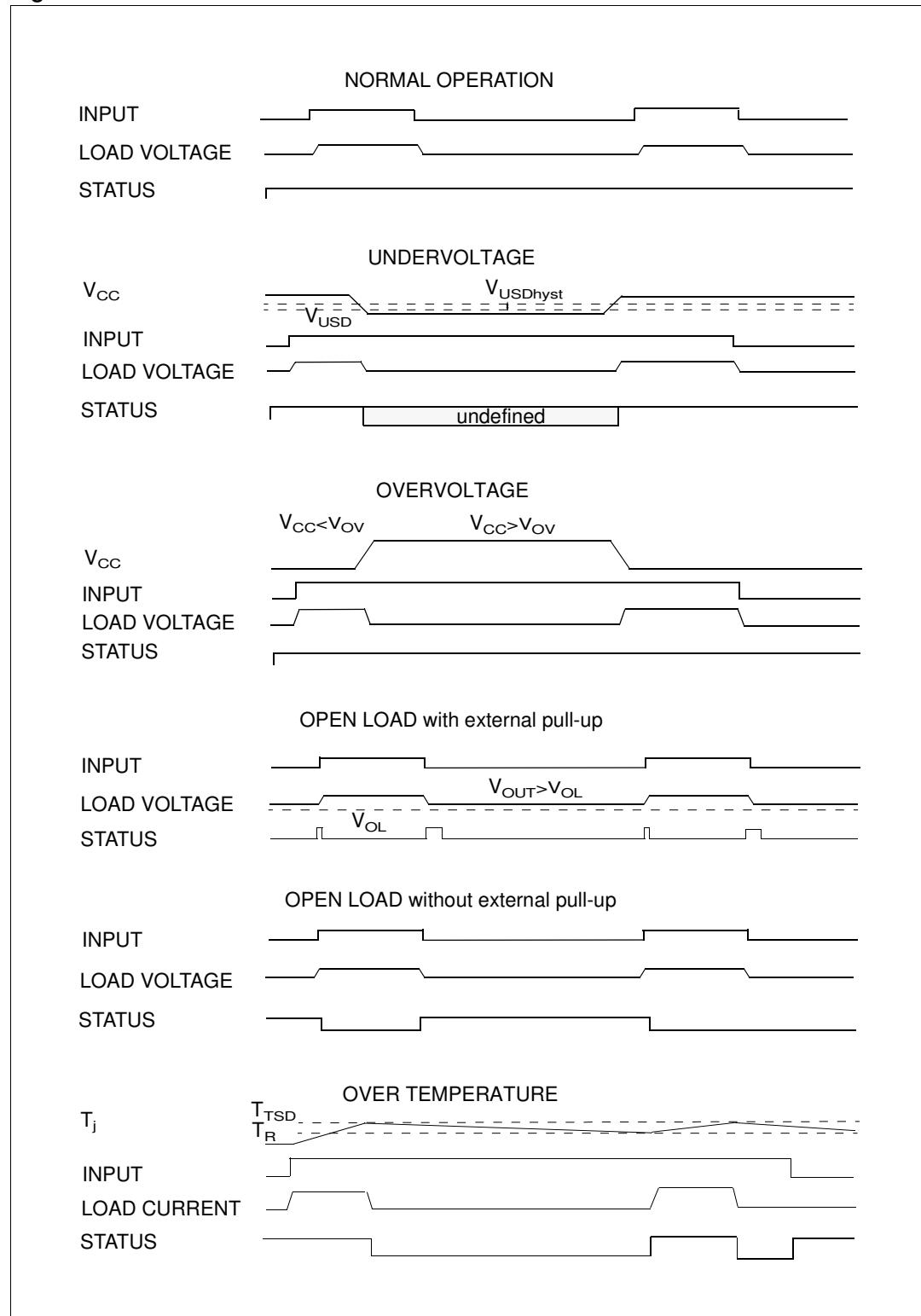
Table 8. Electrical transient requirements on V_{CC} pin (part 2/3)

| ISO T/R 7637/1 test pulse | Test levels results | | | |
|------------------------------|---------------------|----|-----|----|
| | I | II | III | IV |
| 1 | C | C | C | C |
| 2 | C | C | C | C |
| 3a | C | C | C | C |
| 3b | C | C | C | C |
| 4 | C | C | C | C |
| 5 | C | E | E | E |

Table 9. Electrical transient requirements on V_{CC} pin (part 3/3)

| Class | Contents |
|-------|---|
| C | All functions of the device are performed as designed after exposure to disturbance. |
| E | One or more functions of the device is not performed as designed after exposure to disturbance and cannot be returned to proper operation without replacing the device. |

Figure 6. Waveforms



2.4 Electrical characteristics curves

Figure 7. Off-state output current

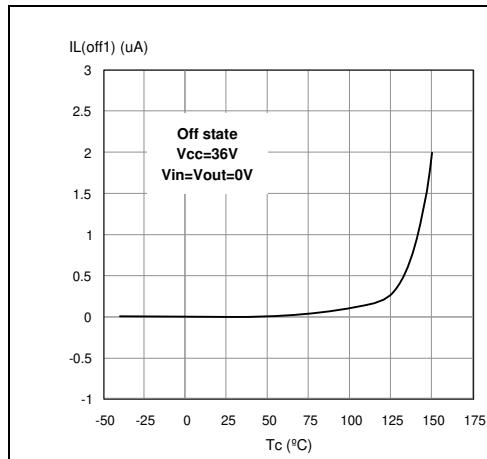


Figure 8. High level input current

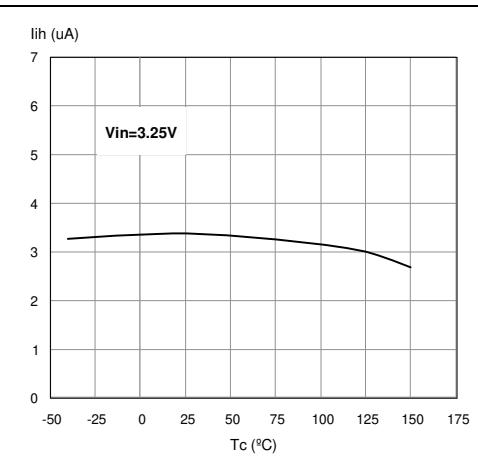


Figure 9. Input clamp voltage

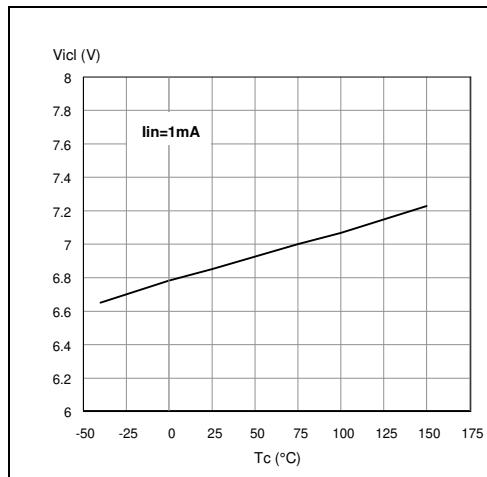


Figure 10. Status leakage current

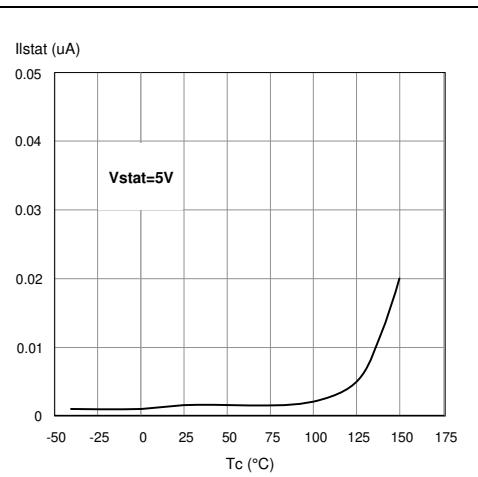


Figure 11. Status low output voltage

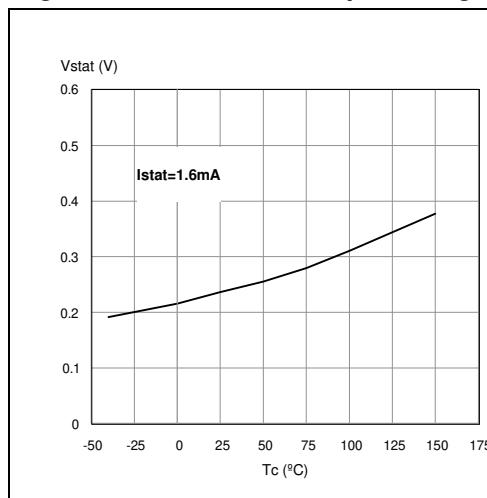


Figure 12. Status clamp voltage

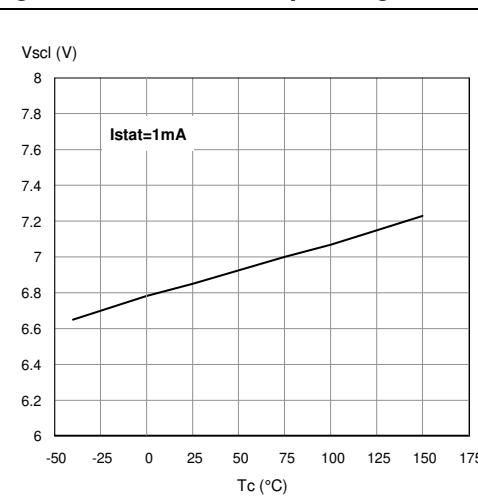


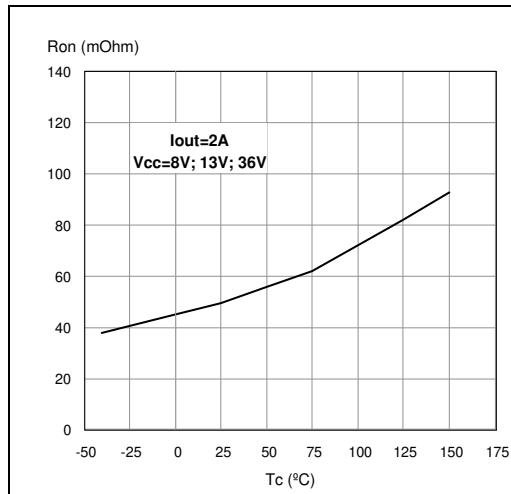
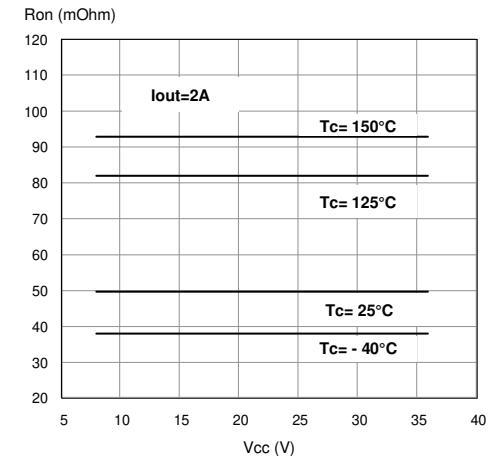
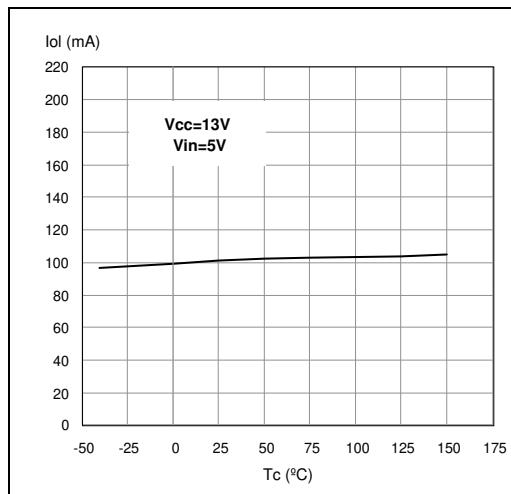
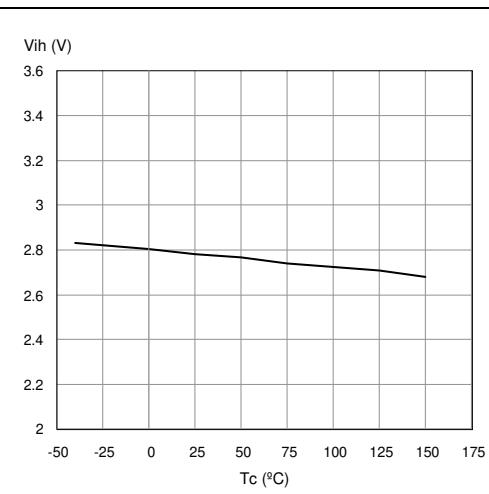
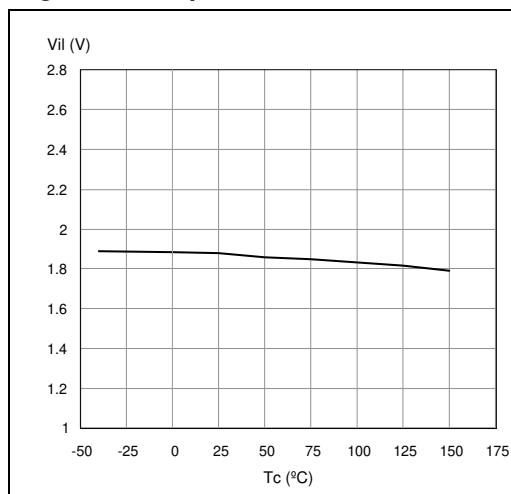
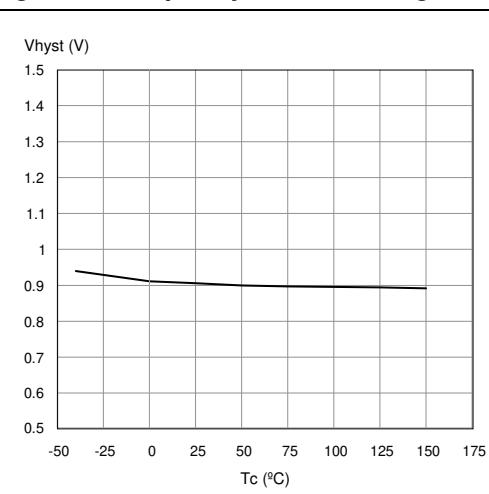
Figure 13. On-state resistance vs T_{case} **Figure 14. On-state resistance vs V_{cc}** **Figure 15. Open-load on-state detection threshold****Figure 16. Input high level threshold****Figure 17. Input low level****Figure 18. Input hysteresis voltage**

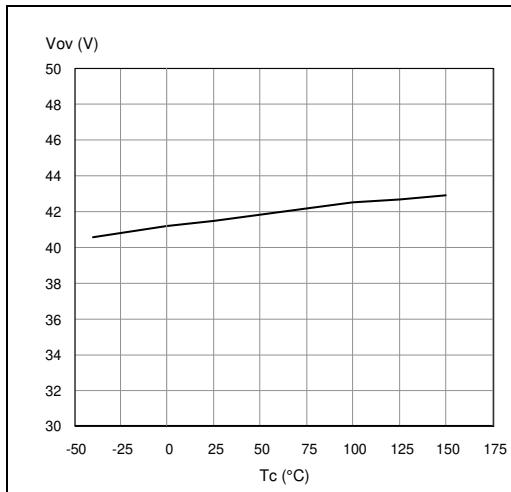
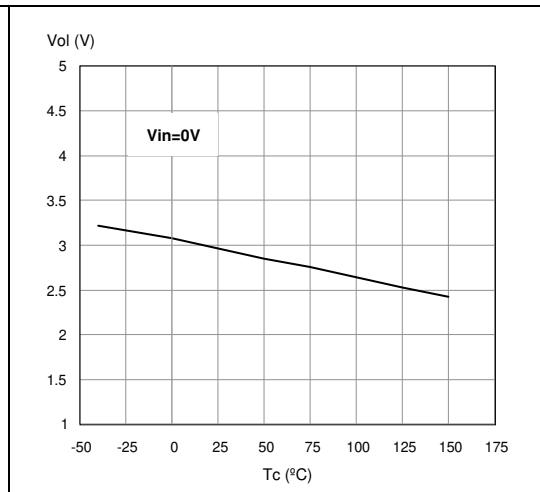
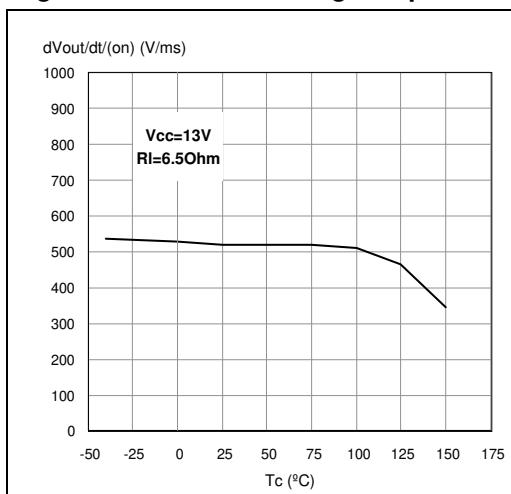
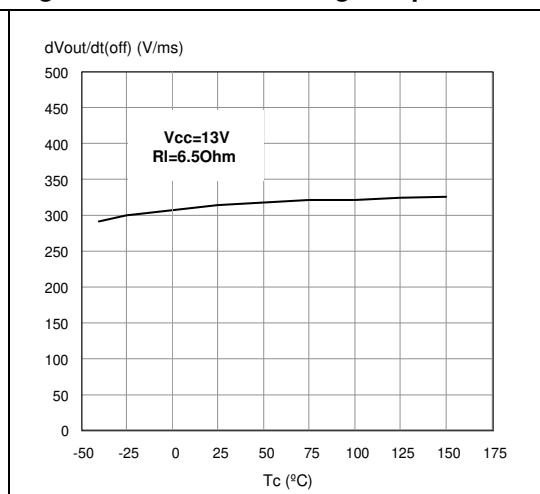
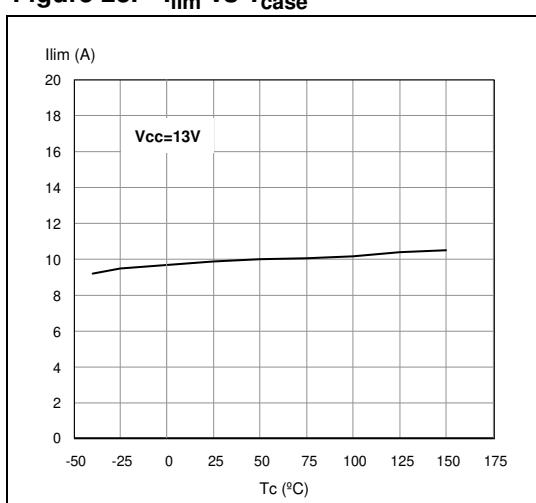
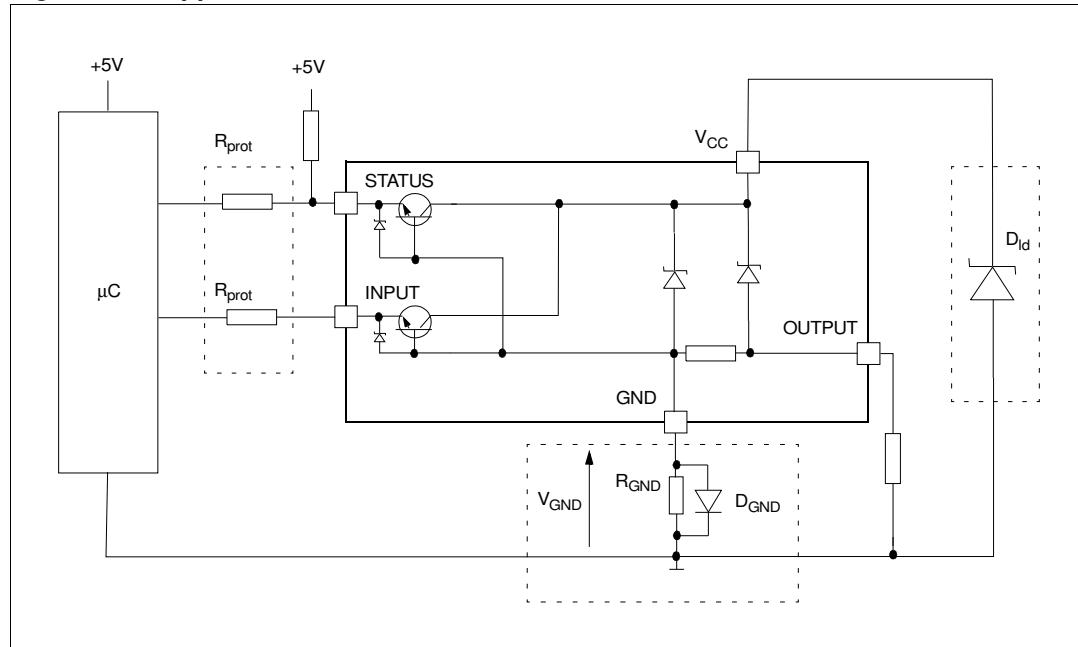
Figure 19. Overvoltage shutdown**Figure 20. Open-load off-state voltage detection threshold****Figure 21. Turn-on voltage slope****Figure 22. Turn-off voltage slope****Figure 23. I_{lim} vs T_{case}** 

Figure 24. Application schematic

2.5

GND protection network against reverse battery

Solution 1: resistor in the ground line (R_{GND} only). This can be used with any type of load.

The following is an indication on how to dimension the R_{GND} resistor.

1. $R_{GND} \leq 600 \text{ mV} / (I_{S(on)\max})$.
2. $R_{GND} \geq (-V_{CC}) / (-I_{GND})$

where $-I_{GND}$ is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device datasheet.

Power dissipation in R_{GND} (when $V_{CC} < 0$: during reverse battery situations) is:

$$P_D = (-V_{CC})^2 / R_{GND}$$

This resistor can be shared amongst several different HSDs. Please note that the value of this resistor should be calculated with formula (1) where $I_{S(on)\max}$ becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not shared by the device ground then the R_{GND} produces a shift ($I_{S(on)\max} * R_{GND}$) in the input thresholds and the status output values. This shift varies depending on how many devices are on in the case of several high side drivers sharing the same R_{GND} .

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then ST suggests to utilize solution 2 (see below).

Solution 2: diode (D_{GND}) in the ground line A resistor ($R_{GND} = 1 \text{ k}\Omega$) should be inserted in parallel to D_{GND} if the device drives an inductive load.

This small signal diode can be safely shared amongst several different HSDs. Also in this case, the presence of the ground network will produce a shift ($\approx 600 \text{ mV}$) in the input threshold and in the status output values if the microprocessor ground is not common to the

device ground. This shift will not vary if more than one HSD shares the same diode/resistor network.

Series resistor in input and status lines are also required to prevent that, during battery voltage transient, the current exceeds the absolute maximum rating.

Safest configuration for unused input and status pin is to leave them unconnected.

2.6 Load dump protection

D_{ld} is necessary (voltage transient suppressor) if the load dump peak voltage exceeds the V_{CC} max DC rating. The same applies if the device is subject to transients on the V_{CC} line that are greater than the ones shown in the ISO 7637-2: 2004(E) table.

2.7 Microcontroller I/Os protection

If a ground protection network is used and negative transient are present on the V_{CC} line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line to prevent the microcontroller I/O pins to latch-up.

The value of these resistors is a compromise between the leakage current of microcontroller and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of microcontroller I/Os.

$$-V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH\mu C} - V_{IH} - V_{GND}) / I_{IHmax}$$

Calculation example:

For $V_{CCpeak} = -100$ V and $I_{latchup} \geq 20$ mA; $V_{OH\mu C} \geq 4.5$ V

$$5 \text{ k}\Omega \leq R_{prot} \leq 65 \text{ k}\Omega$$

Recommended values: $R_{prot} = 10 \text{ k}\Omega$.

2.8 Open-load detection in off-state

Off-state open-load detection requires an external pull-up resistor (R_{PU}) connected between output pin and a positive supply voltage (V_{PU}) like the +5V line used to supply the microprocessor.

The external resistor has to be selected according to the following requirements:

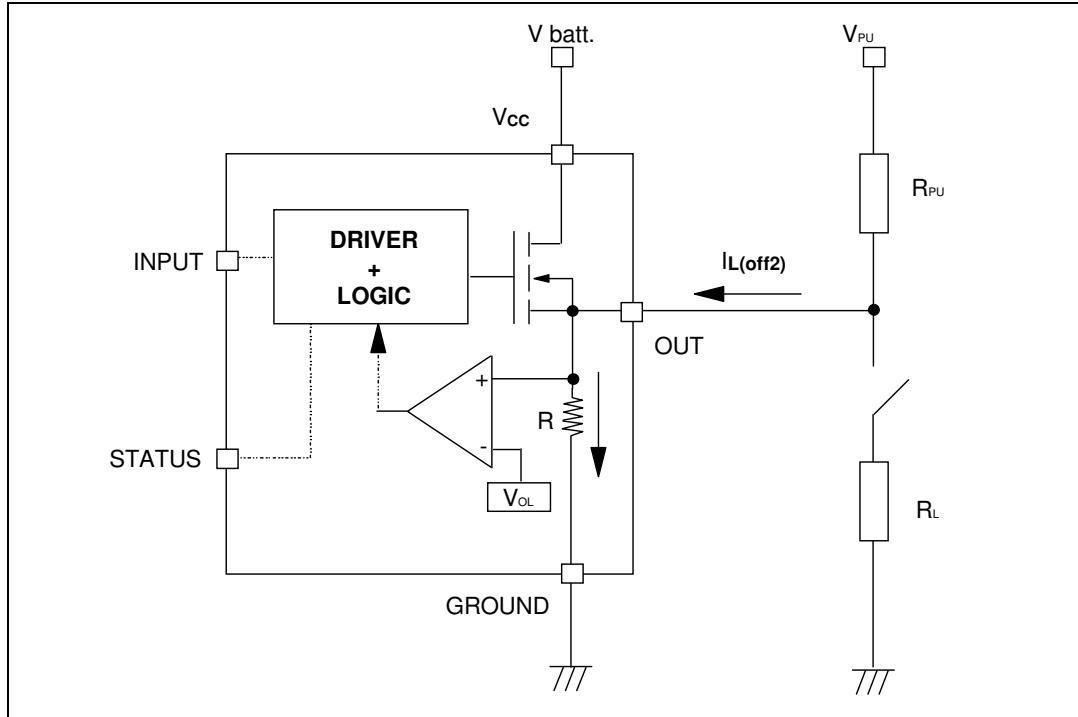
1. no false open-load indication when load is connected: in this case we have to avoid V_{OUT} to be higher than V_{OLmin} ; this results in the following condition

$$V_{OUT} = (V_{PU} / (R_L + R_{PU}))R_L < V_{OLmin}$$
2. no misdetection when load is disconnected: in this case the V_{OUT} has to be higher than V_{OLmax} ; this results in the following condition $R_{PU} < (V_{PU} - V_{OLmax}) / I_{L(off2)}$.

Because $I_{S(OFF)}$ may significantly increase if V_{out} is pulled high (up to several mA), the pull-up resistor R_{PU} should be connected to a supply that is switched off when the module is in standby.

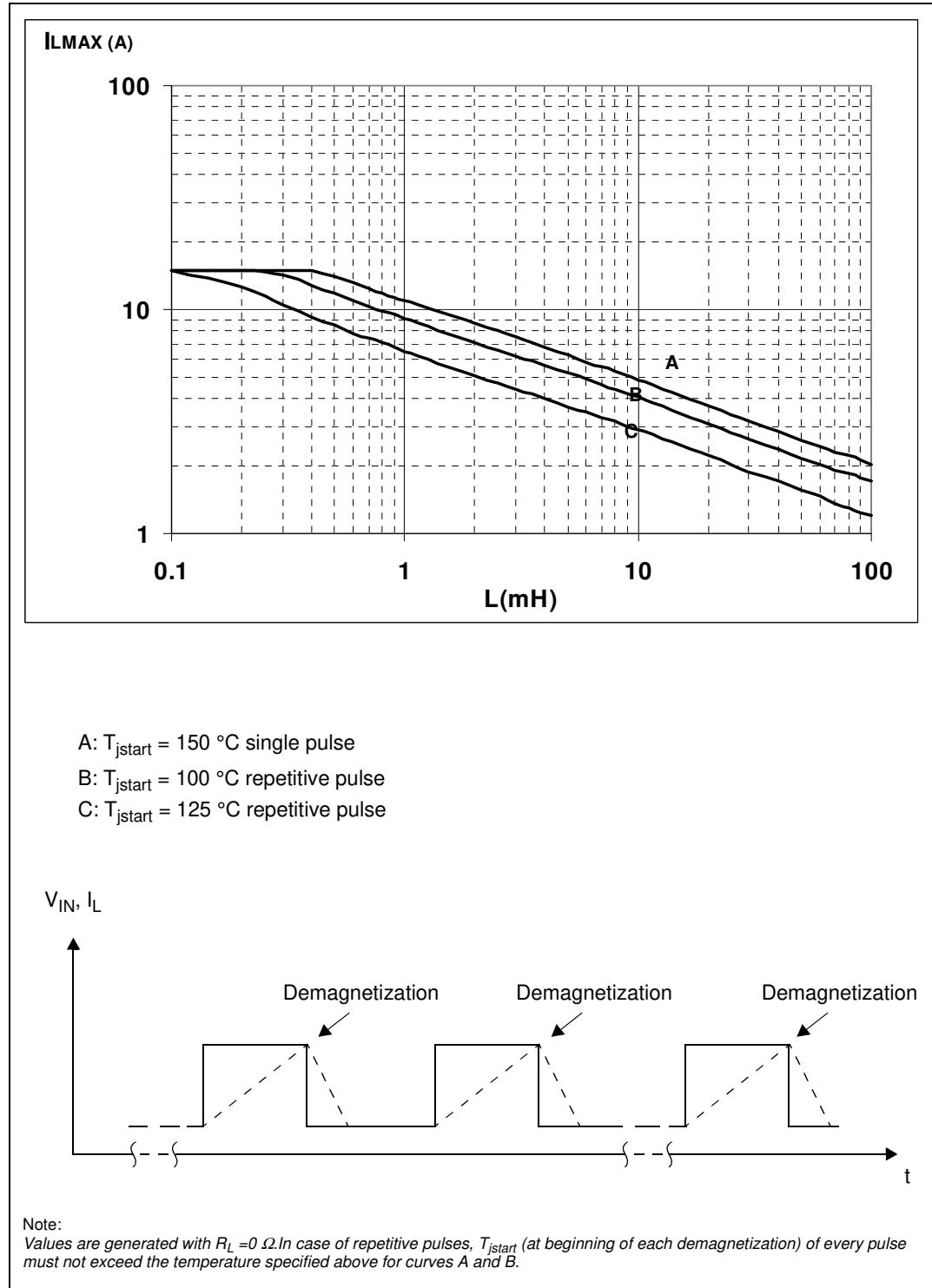
The values of V_{OLmin} , V_{OLmax} and $I_{L(off2)}$ are available in the electrical characteristics section.

Figure 25. Open-load detection in off-state



2.9 SO-8 maximum demagnetization energy ($V_{CC} = 13.5$ V)

Figure 26. SO-8 maximum turn-off current versus inductance



3 Package and PCB thermal data

3.1 SO-8 thermal data

Figure 27. PC board

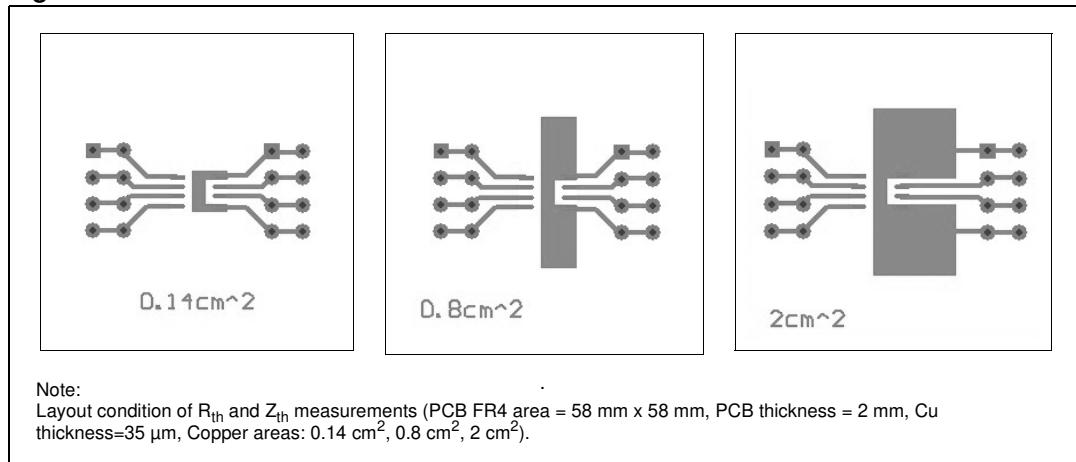


Figure 28. $R_{thj\text{-amb}}$ vs PCB copper area in open box free air condition

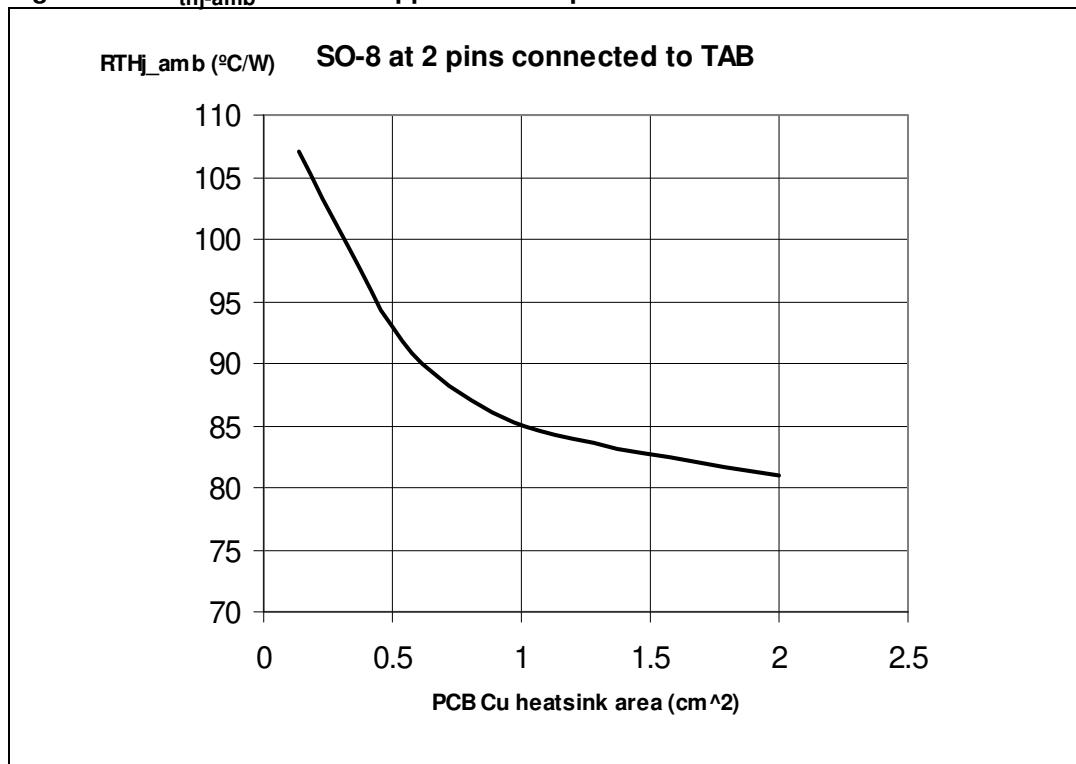
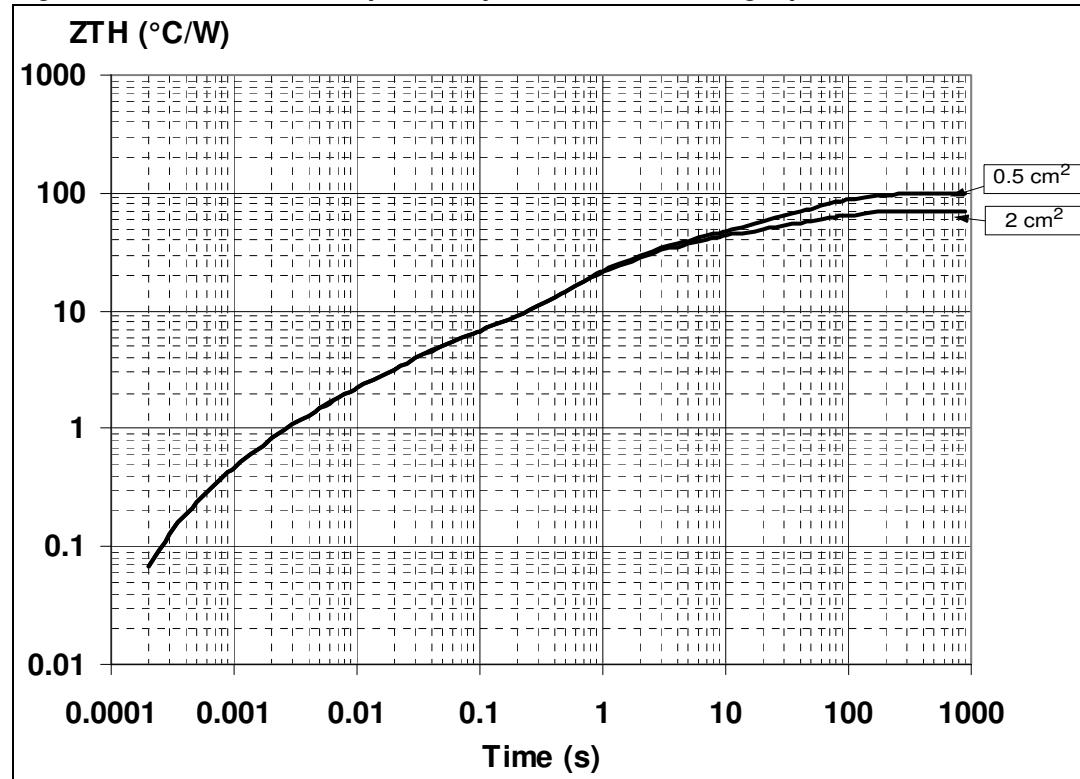


Figure 29. SO-8 thermal impedance junction ambient single pulse



Equation 1: pulse calculation formula

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THtp}(1 - \delta)$$

where $\delta = t_p/T$

Figure 30. Thermal fitting model of a single channel

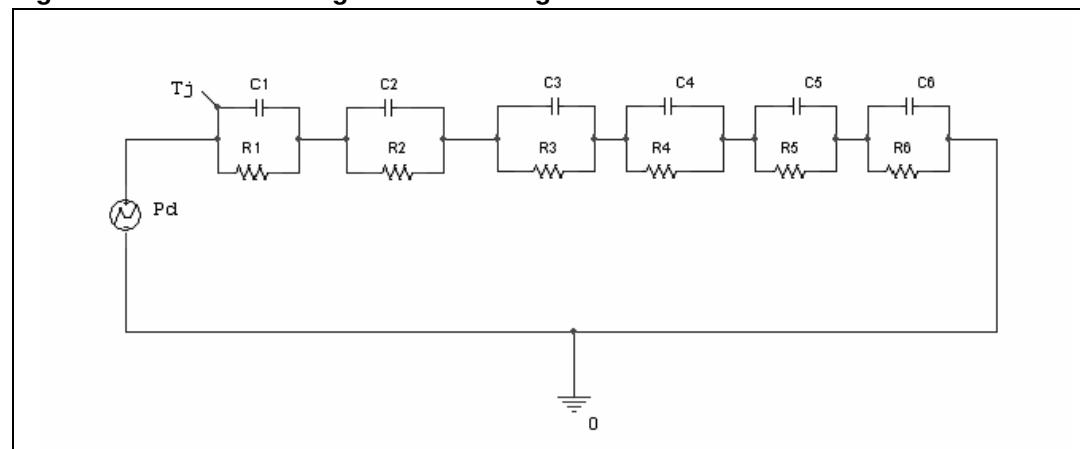


Table 10. Thermal parameter

| Area/island (cm ²) | 0.5 | 2 |
|--------------------------------|--------|----|
| R1 (°C/W) | 0.05 | |
| R2 (°C/W) | 0.8 | |
| R3 (°C/W) | 3.5 | |
| R4 (°C/W) | 21 | |
| R5 (°C/W) | 16 | |
| R6 (°C/W) | 58 | 28 |
| C1 (W·s/°C) | 0.006 | |
| C2 (W·s/°C) | 0.0026 | |
| C3 (W·s/°C) | 0.0075 | |
| C4 (W·s/°C) | 0.045 | |
| C5 (W·s/°C) | 0.35 | |
| C6 (W·s/°C) | 1.05 | 2 |

4 Package and packing information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.

ECOPACK® is an ST trademark.

4.1 SO-8 package information

Figure 31. SO-8 package dimensions

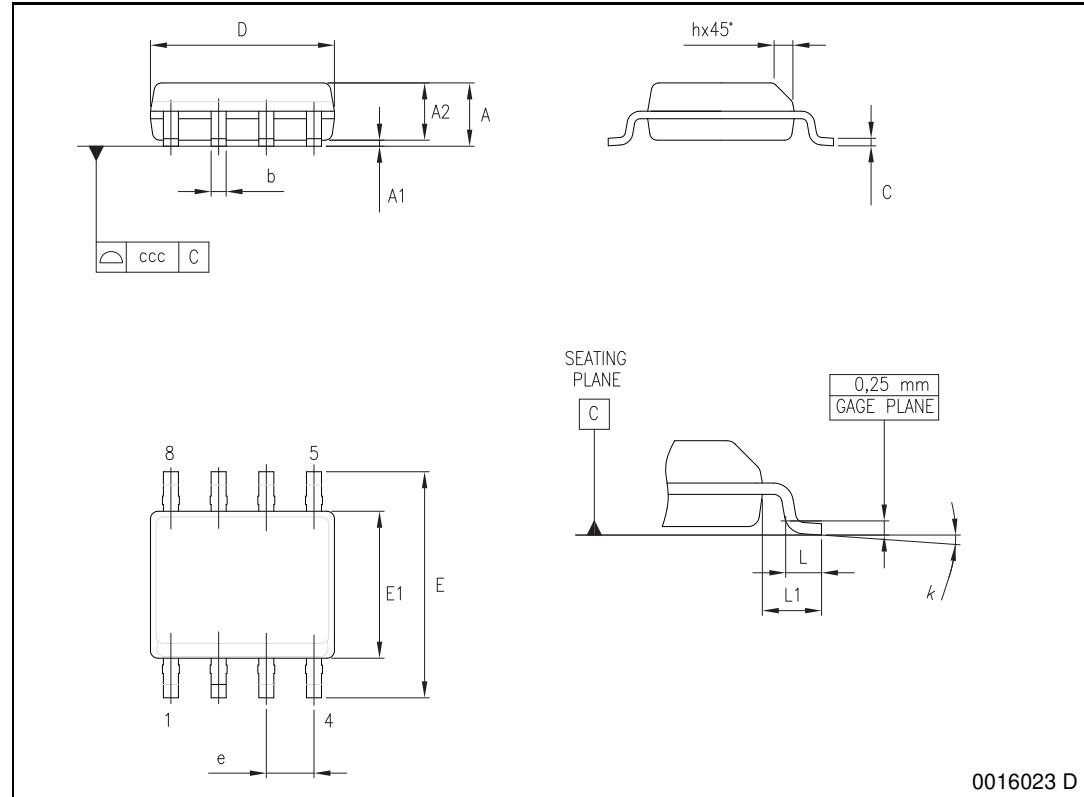


Table 11. SO-8 mechanical data

| Dim. | mm | | |
|-------------------|------|------|------|
| | Min. | Typ. | Max. |
| A | | | 1.75 |
| A1 | 0.10 | | 0.25 |
| A2 | 1.25 | | |
| b | 0.28 | | 0.48 |
| c | 0.17 | | 0.23 |
| D ⁽¹⁾ | 4.80 | 4.90 | 5.00 |
| E | 5.80 | 6.00 | 6.20 |
| E1 ⁽²⁾ | 3.80 | 3.90 | 4.00 |
| e | | 1.27 | |
| h | 0.25 | | 0.50 |
| L | 0.40 | | 1.27 |
| L1 | | 1.04 | |
| k | 0° | | 8° |
| ccc | | | 0.10 |

1. Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusions or gate burrs shall not exceed 0.15 mm in total (both side).
2. Dimension "E1" does not include interlead flash or protrusions. Interlead flash or protrusions shall not exceed 0.25 mm per side.

4.2 SO-8 packing information

The devices can be packed in tube or tape and reel shipments (see the [Device summary on page 1](#)).

Figure 32. SO-8 tube shipment (no suffix)

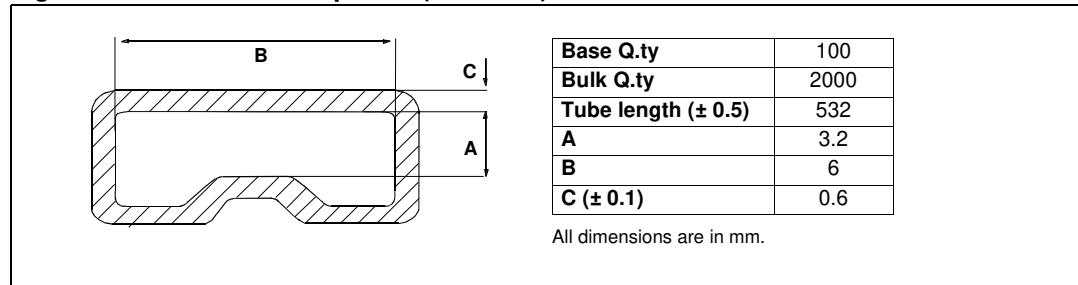


Figure 33. SO-8 tape and reel shipment (suffix "TR")

